

Search Notes

Application/Control No.

10/695,607

Examiner

Duc M. Nguyen

Applicant(s)/Patent under Reexamination

LAPID, ADAM

Art Unit

2685

SEARCHED

Class	Subclass	Date	Examiner
455	126 127.2		
	219 232.1		
	234.1		
	239.1		
	240.1		
	245.1		
	249.1		
	250.1		
330	256		
	266		
	272		
289	8/17/2005	DN	

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner